# MB8464A-80/-80L/-80LL/-10/-10L/-10LL/-15/-15L/-15LL CMOS 64K BIT LOW POWER SRAM

#### 8K Words x 8 Bits CMOS Static RAM with Low Power and Data Retention

The Fujitsu MB8464A is a 8,192 words x 8 bits static random access memory fabricated with a CMOS silicon gate process. The memory uses asynchronous circuitry and may be maintained in any state for an indefinite period of time. All pins are TTL compatible and a single +5 V power supply is required.

The MB8464A has low power dissipation, low cost, and high performance, and it is ideally suited for use in microprocessor systems and other applications where fast access time and ease of use are required.

Organization:

8,192 words x 8 bits

Access time:

80 ns max. (MB8464A-80/-80L/-80LL) (MB8464A-10/-10L/-10LL)

100 ns max. 150 ns max.

(MB8464A-15/-15L/-15LL)

Static operation: no clock required

TTL compatible inputs and outputs

Three-state outputs

Common data inputs and outputs

Single +5 V power supply ±10% tolerance

Low power standby: 11 mW max. (MB8464A-80/-10/-15)

0.55 mW max. (MB8464A-80L/-10L/-15L) 0.55 mW max. (MB8464A-80LL/-10LL/-15LL)

(MB8464A-80/-10/-15) Data retention current:

25 LIA max. (MB8464A-80L/-10L/-15L)

2 LIA max. at 0°C to 40°C

(MB8464A-80LL/-10LL/-15LL)

Data retention: 2.0 V min.

Standard 28-pin Plastic Packages:

DIP (600 mil)

MB8464A-xx(L/LL)P Skinny DIP MB8464A-xx(L/LL)PSK (300 mil) SOP (450 mil) MB8464A-xx(L/LL)PF

Standard 32-pad Ceramic Package: MB8464A-xx(L/LL)CV LCC (metal seal)

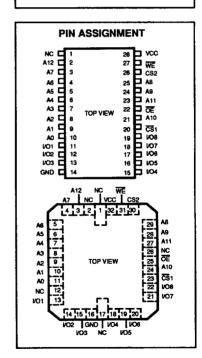
Absolute Maximum Ratings (See Note)

Rating		Symbol	Value	Unit	
Supply Voltage		V <sub>cc</sub>	-0.5 to +7.0	V	
Input Voltage		V <sub>IN</sub>	-0.5* to V <sub>CC</sub> +0.5	V	
Output Voltage		Vout	-0.5 to V <sub>CC</sub> +0.5	٧	
Temperature Under Bis	Temperature Under Bias		-10 to +85	°C	
Storage Temperature Ceramic		T	-65 to +150	°c	
Range	Plastic	T <sub>STG</sub>	-45 to +125	•0	

\* -2.0 V for pulse width less than 20 ns.

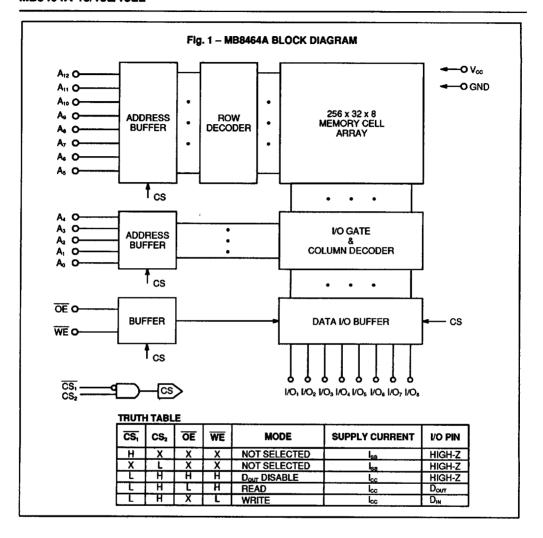
Note: Permanent device damage may occur if absolute maximum ratings are exceeded. Functional operation should be restricted to the conditions as detailed in the operation sections of this data sheet. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

PLASTIC PACKAGE PLASTIC PACKAGE DIP-28P-M02 DIP-28P-M04 PLASTIC PACKAGE CERAMIC PACKAGE FPT-28P-M02 LCC-32C-A02



This device contains circultry to protect the inputs against damage due to high static voltages or electric fields. Howe is advised that normal precautions be taken to avoid appli ny voltage higher than maximum rated voltages to this high edance circuit.

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# CAPACITANCE (TA= 25° C, f = 1MHz)

Parameter	Symbol	Min	Тур	Max	Unit
I/O Capacitance (V <sub>I/O</sub> =0V)	C <sub>ivo</sub>			8	ρF
Input Capacitance (V <sub>N</sub> =0V)	C <sub>IN</sub>			6	рF

### RECOMMENDED OPERATING CONDITIONS

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(Referenced to GND)

Parameter	Symbol	Min	Тур	Max	Unit
Supply Voltage	Vcc	4.5	5.0	5.5	٧
Ambient Temperature	TA	0		70	°C

### **DC CHARACTERISTICS**

(Recommended operating conditions unless otherwise noted.)

Parameter	Symbol				MB8464A-80L/80LL 10L/10LL/15L/15LL		Test Condition	
		Min	Max	Min	Max			
Standby Supply Current	l <sub>se1</sub>		2		0.1	mA	CS <sub>2</sub> ≤0.2V, <del>CS</del> <sub>1</sub> ≥V <sub>00</sub> −0.2V (CS <sub>2</sub> ≤0.2V or CS <sub>2</sub> ≥V <sub>00</sub> −0.2V)	
	I <sub>382</sub>		3		3	mA	CS <sub>1</sub> =V <sub>IH</sub> or CS <sub>2</sub> =V <sub>IL</sub>	
Active Supply Current	l <sub>cc1</sub>		50		50	mA	CS <sub>1</sub> =V <sub>IL</sub> , CS <sub>2</sub> =V <sub>IH</sub> V <sub>IH</sub> =V <sub>IH</sub> or V <sub>IL</sub> , I <sub>OUT</sub> =0mA	
Operating Supply Current	l <sub>CC2</sub>		60		60	mA	Cycle=Min., Duty=100% l <sub>out</sub> =0mA	
Input Leakage Current	lu	-1	1	-1	-1	μА	V <sub>IN</sub> =0V to V <sub>CC</sub>	
Output Leakage Current	luo	-2	2	-2	2	μА	V <sub>ICC</sub> =0V to V <sub>CC</sub> <u>CS</u> <sub>1</sub> =V <sub>IH</sub> or <u>CS</u> <sub>2</sub> =V <sub>IL</sub> or <u>OE</u> =V <sub>IH</sub> or <u>WE</u> =V <sub>L</sub>	
Input Low Voltage	V <sub>IL</sub>	-2.0*	8.0	-2.0*	0.8	V		
Input High Voltage	V <sub>IH</sub>	2.2	V <sub>cc</sub> +0.3	2.2	V <sub>cc+</sub> 0.3	٧		
Output High Voltage	VoH	2.4		2.4		٧	l <sub>oн=</sub> -1.0mA	
Output Low Voltage	Vol		0.4		0.4	٧	I <sub>ct</sub> =2.1mA	

\* -2.0V Min for pulse width less than 20ns. (V<sub>L</sub> Min.=-0.3V at DC level)

#### Fig. 2 - AC TEST CONDITIONS

• Input Pulse Levels:

0.6V to 2.4V

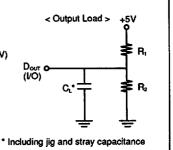
• Input Pulse Rise and Fall Times: 5ns (Transient Time between 0.8V and 2.2V)

• Timing Reference Levels:

Input : V<sub>IL</sub>=0.8V, V<sub>IH</sub>=2.2V Output : V<sub>OL</sub>=0.8V, V<sub>OH</sub>=2.0V

· Output Load:

	R₁	R <sub>2</sub>	Cı	Parameters Measured
Load I	1.8kΩ	990Ω	100pF	except touz, touz, touz, touz, twuz and twuz
Load II	1.8kΩ	990Ω	5pF	touz, touz, touz, touz touz twuz, and twuz

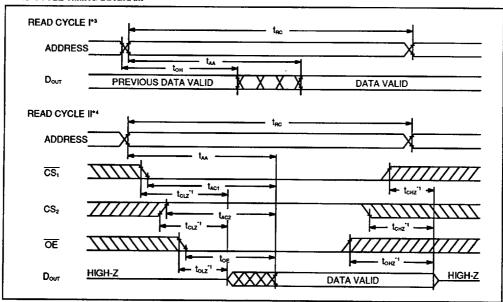


## **AC CHARACTERISTICS**

(Recommended operating conditions unless otherwise noted) **READ CYCLE** 

Parameter	Symbol	MB8464A- 80/80L/80LL		MB8464A- 10/10L/10LL		MB8464A- 15/15L/15LL		Unit
		Min	Max	Min	Max	Min	Max	1
Read Cycle Time	t <sub>RC</sub>	80		100		150		ns
Address Access Time	taa		80		100		150	ns
CS <sub>1</sub> Access Time	t <sub>AC1</sub>		80		100		150	r ns
CS₂ Access Time	t <sub>AC2</sub>		80		100		150	ns
Output Enable to Output Valid	toE		35		45		55	ns
Output Hold from Address Change	t <sub>oH</sub>	10		10		10		ns
Chip Select to Output Low-Z*1	t <sub>CLZ</sub>	10		10		10		ns
Output Enable to Output Low-Z*1	toız	5		5		5		ns
Chip Select to Output High-Z*1	t <sub>cHZ</sub>		35		35		40	ns
Output Enable to Output High-Z*1	tonz		30		35		40	ns

#### READ CYCLE TIMING DIAGRAM \*2

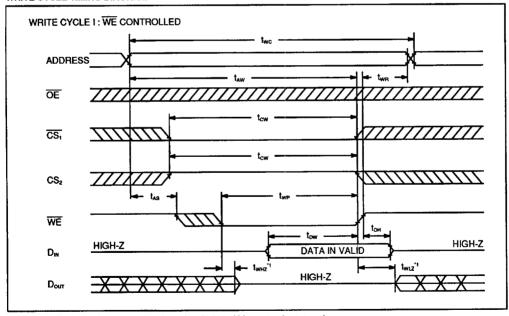


Note:

- \*1 Transition is measured at the point of ±500mV from steady state voltage.
- \*2 WE is high for Read Cycle.
- \*3 Device is continuously selected, CS1=OE=VIL CS2=VIH.
- \*4 Address valid prior to or coincident with CS1 transition low, CS2 transition high.

Parameter	Symbol	MB8464A- 80/80L/80LL		MB8464A- 10/10L/10LL		MB8464A- 15/15L/15LL		Unit
		Min	Max	Min	Max	Min	Max	
Write Cycle Time	t <sub>wc</sub>	80		100		150		ns
Address Valid to End of Write	taw	60		80		100		ns
Chip Select to End of Write	tow	60		80		100		ns
Data Valid to End of Write	t <sub>DW</sub>	30		35		40		ns
Data Hold Time	t <sub>DH</sub>	5		5		5		ns
Write Pulse Width	t <sub>we</sub>	60		70		90		ns
Address Setup Time	tas	0		0		0		ns
Write Recovery Time	t <sub>we</sub>	5		5		5		ns
Write Enable to Output Low-Z*1	twcz	5		5		5		ns
Write Enable to Output High-Z*1	t <sub>wrz</sub>		30		35		40	ns

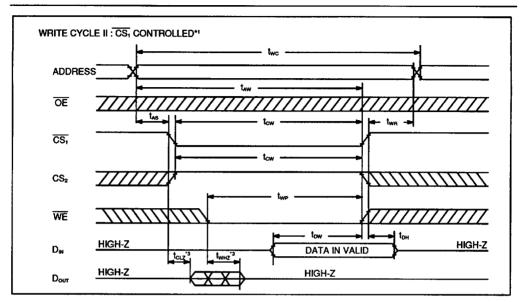
#### WRITE CYCLE TIMING DIAGRAM \*2

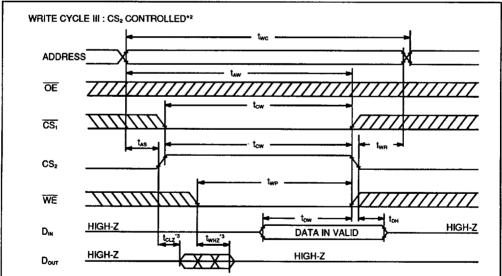


Note: \*1 Transition is measured at the point of ±500mV from steady state voltage.

\*2 If OE, OS₁ and CS₂ are in the READ Mode during this period, I/O pins are in the output state so that the input signals of opposite phase to the outputs must not be applied.

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Note: \*1 If  $\overline{\text{OE}}$ ,  $\text{CS}_2$  and  $\overline{\text{WE}}$  are in the READ Mode during this period, I/O pins are in the output state so that the input signals of opposite phase to the outputs must not be applied.

\*2 If OE, CS, and WE are in the READ Mode during this period, I/O pins are in the output state so that the input signals of opposite phase to the outputs must not be applied.

\*3 Transition is measured at the point of ±500mV from steady state voltage.

3

### **DATA RETENTION CHARACTERISTICS**

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(Recommended operating conditions unless otherwise noted)

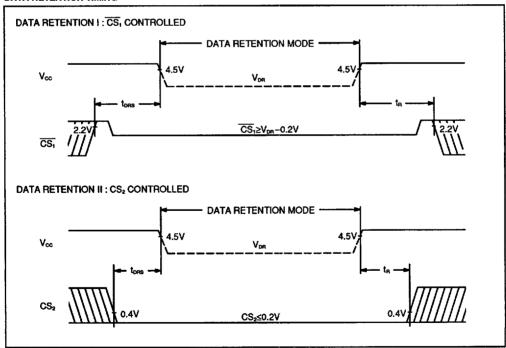
Parameter  Data Retention Supply Voltage		Symbol	Min	Тур	Max	Unit
		V <sub>DR</sub>	2.0		5.5	V
	Standard				1.0	mΑ
Data Retention Supply Current*2	L-Version	I <sub>DR</sub>		1.0	25	μА
Coppi, Contoni	LL-Version*3			1.0	2.0	μА
Data Retention Setup Time		toes	0			ns
Operation Recovery Time		t <sub>R</sub>	t <sub>RC</sub>			ns

Note:

\*2  $\underline{CS_2}$  controlled:  $V_{DR}$ =3.0V,  $\underline{CS_2}$ ≤0.2V  $\underline{\overline{CS_1}}$  controlled:  $V_{DR}$ =3.0V,  $\underline{\overline{CS_1}}$ > $V_{DR}$ =0.2V ( $\underline{CS_2}$ ≤0.2V or  $\underline{CS_2}$ ≥ $V_{DR}$ =0.2V)

\*3 Vpe=3.0V, Ta=0°C to 40°C

#### **DATA RETENTION TIMING**



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### TYPICAL CHARACTERISTICS CURVES

Fig. 3 - NORMALIZED POWER SUPPLY CURRENT vs. SUPPLY VOLTAGE

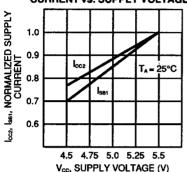


Fig. 5 - NORMALIZED POWER SUPPLY **CURRENT vs. CYCLE TIME** 

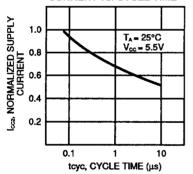


Fig. 7 - NORMALIZED ACCESS TIME vs. SUPPLY VOLTAGE

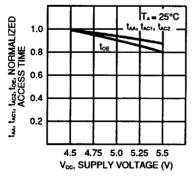


Fig. 4 - NORMALIZED POWER SUPPLY **CURRENT VS. AMBIENT TEMPERATURE** 

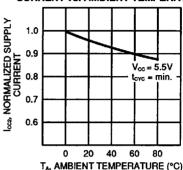


Fig. 6 - NORMALIZED POWER SUPPLY

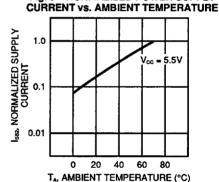
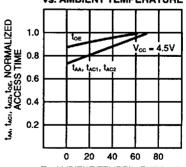
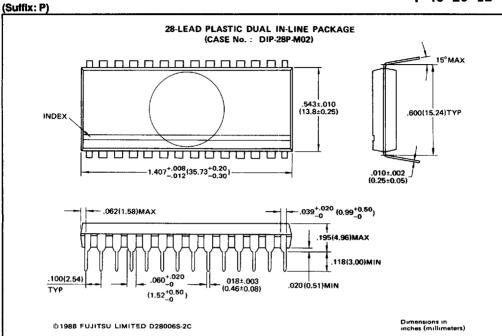


Fig. 8 - NORMALIZED ACCESS TIME VS. AMBIENT TEMPERATURE

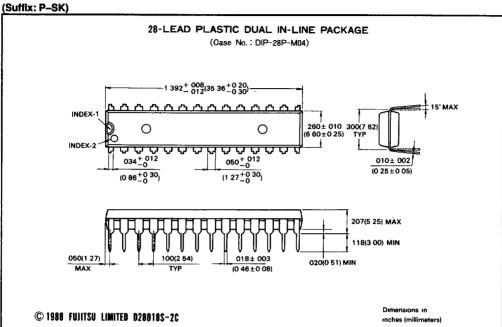


## **PACKAGE DIMENSIONS**

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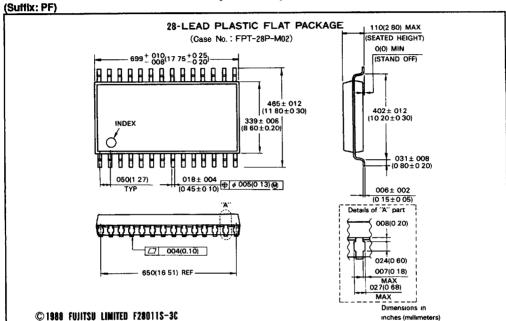


# **PACKAGE DIMENSIONS**



# **PACKAGE DIMENSIONS (Cont'd)**

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# PACKAGE DIMENSIONS (Cont'd)

